

### **Description**

#### **40V N-CHANNEL ENHANCEMENT MODE POWER MOSFET**

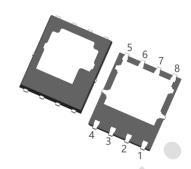
#### **Features**

- Device Rating V<sub>DS</sub> = 40V, I<sub>D</sub> = 568A
- $R_{DS(ON)} = 0.51 \text{m}\Omega \text{ (typ.)} @ V_{GS} = 10 \text{V, } I_D = 50 \text{A}$
- Proprietary High Density Trench Technology
- RoHS Compliant & Halogen-Free

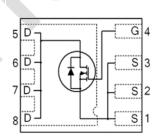
#### **Application**

- High performance DC/DC
- SR
- Motor Driving

#### **Package**



DFN 5\*6-8L Dual Cool JFG568N40LC



### Absolute Maximum Ratings Tc=25℃ unless otherwise specified

Symbol	Parameter		Max.	Units	
V <sub>DS</sub>	Drain-Source Voltage		40	V	
V <sub>GS</sub>	Gate-Source Voltage		± 20	V	
lo	Continuous Drain Current, VGS @ 10V note1	T <sub>C</sub> = 25°C	568	А	
		T <sub>C</sub> = 100°C	359	А	
I <sub>DM</sub>	Pulsed Drain Current note2		1482	А	
P <sub>D</sub>	Power Dissipation note4	T <sub>C</sub> = 25°C	312	W	
	Power Dissipation	T <sub>A</sub> = 25°C	2.5	W	
Eas	Single Pulsed Avalanche Energy note3		685	mJ	
Rejc	Thermal Resistance, Junction to Case bottom note1		0.4	°C/W	
Rejc	Thermal Resistance, Junction to Case top note1		0.36	°C/W	
R <sub>θ</sub> JA	Junction to Ambient (mounted on 1 inch square PCB)		50	°C/W	
TJ, TSTG	Operating and Storage Temperature Range		-55 to +150	°C	



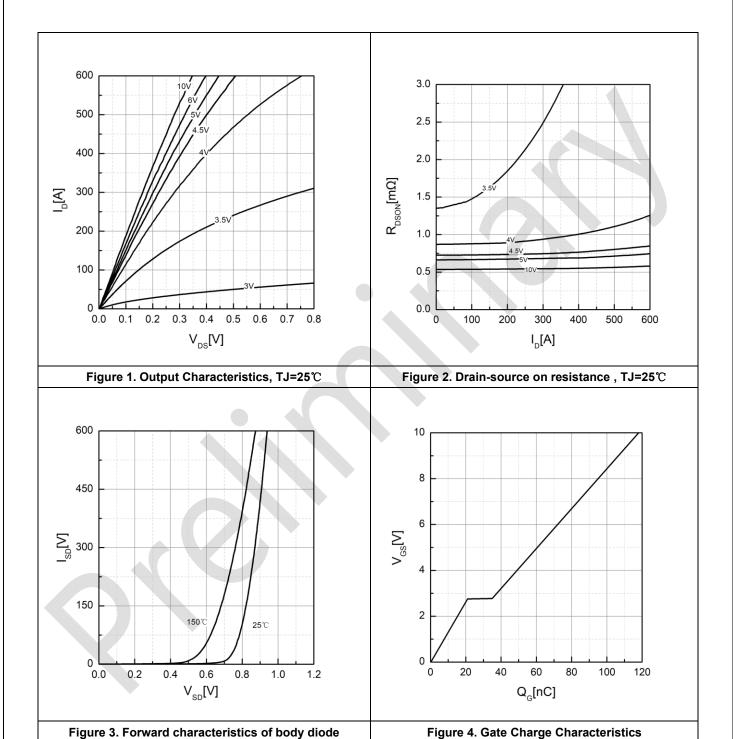
### Electrical Characteristics T<sub>C</sub>=25℃ unless otherwise specified

Symbol	Parameter	Test Condition	Min.	Тур.	Max.	Units
Off Charac	teristic		Į.	•		·
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> = 250µA	40	-	-	V
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =40V,V <sub>GS</sub> = 0V, T <sub>C</sub> = 25°C	-	-	1	μA
		V <sub>DS</sub> =40V,V <sub>GS</sub> = 0V, T <sub>C</sub> = 55°C	-	-	10	μA
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>DS</sub> = 0V, V <sub>GS</sub> = ±20V	-100	-	100	nA
On Charac	teristics					·
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}$ , $I_D = 250 \mu A$	1.3	_	2.3	V
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 10V, I <sub>D</sub> =50A	-	0.51	0.65	mΩ
R <sub>DS(on)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> = 4.5V, I <sub>D</sub> =50A		0.69	0.85	mΩ
<b>g</b> FS	Forward Transconductance	V <sub>DS</sub> = 1V, I <sub>D</sub> =50A		260	-	S
Dynamic C	Characteristics					
Rg	Gate Resistance		-	1.1	-	Ω
Ciss	Input Capacitance		-	7990	-	pF
Coss	Output Capacitance	$V_{DS} = 20V$ , $V_{GS} = 0V$ , f = 1MHz	-	1952	-	pF
Crss	Reverse Transfer Capacitance		-	80	-	pF
Qg	Total Gate Charge	V <sub>DS</sub> =20V,I <sub>D</sub> =50A,V <sub>GS</sub> = 4.5V		56		nC
Qg	Total Gate Charge	$V_{DS}$ =20V, $I_{D}$ = 50A, $V_{GS}$ = 10V	-	118	-	nC
Qgs	Gate-Source Charge		-	21	-	nC
Q <sub>gd</sub>	Gate-Drain("Miller") Charge		-	15	-	nC
Switching	Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time		_	13	-	ns
tr	Turn-On Rise Time	$V_{DD} = 20V, I_D = 20A,$	_	27	-	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_G = 1\Omega$ , $V_{GS} = 10V$	-	42	-	ns
t <sub>f</sub>	Turn-Off Fall Time		-	15	-	ns
Source-Dr	ain Diode Characteristics and Maxim	um Ratings	I	1	<u> </u>	
Is	Maximum Continuous Diode Forward Current note1,5		-	_	260	Α
Ism	Maximum Pulsed Diode Forward Current note2,5		-	-	1482	Α
t <sub>rr</sub>	Reverse Recovery Time	T <sub>J</sub> = 25°C, I <sub>S</sub> = 10A, V <sub>GS</sub> = 0V	-	62	-	ns
Qrr	Reverse Recovery Charge	di/dt = 400A/µs	-	186	-	nC
V <sub>SD</sub> note2	Source to Drain Diode Forward Voltage	T <sub>J</sub> = 25°C, I <sub>S</sub> = 50A, V <sub>GS</sub> = 0V	-	0.77	-	V

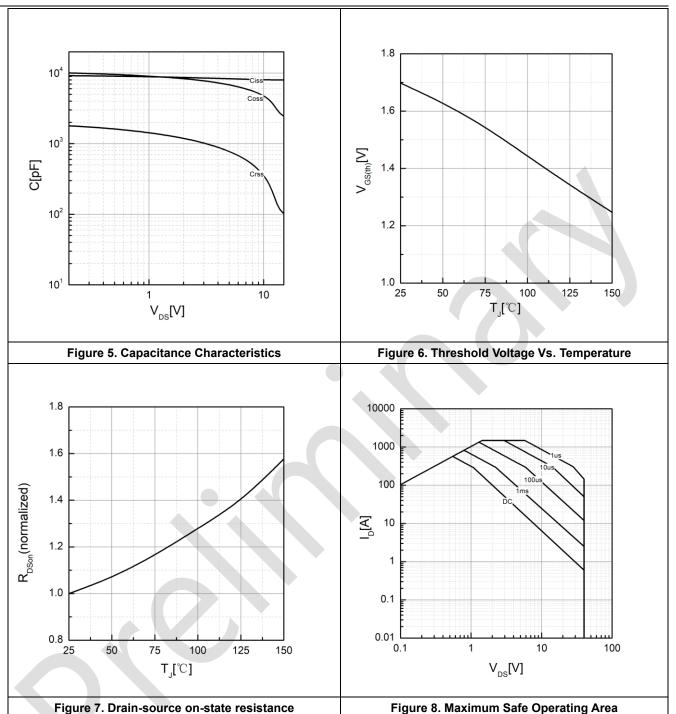
#### Note:

- 1.The data tested by surface mounted on one inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2.The data tested by pulsed, pulse width  $\leq$  300us, duty cycle  $\leq$  2%.
- 3.The EAS data shows Max. rating. The test condition is L=0.1mH,  $I_D$ = 126A.
- 4.The power dissipation is limited by 150  $^{\circ}\text{C}\,$  junction temperature.
- 5.The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub>, in real applications, should be limited by total power dissipation.

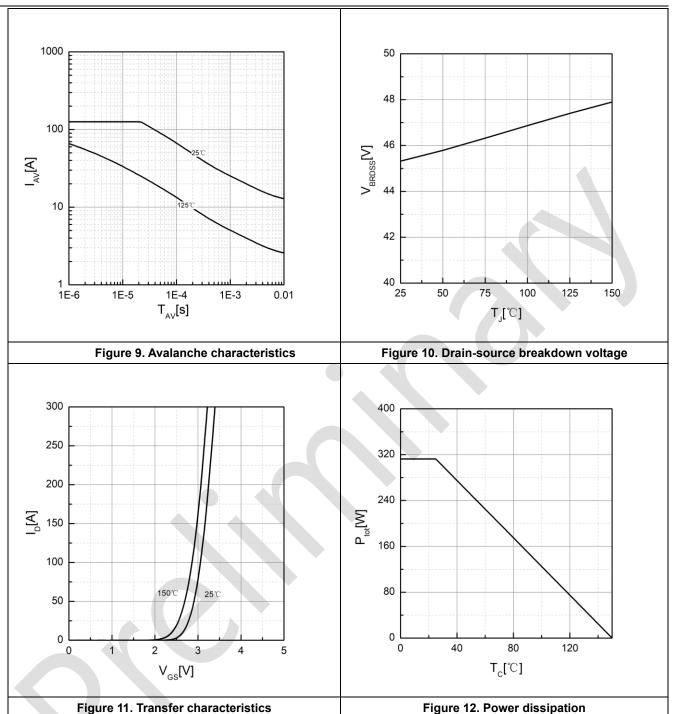
### **Typical Performance Characteristics**



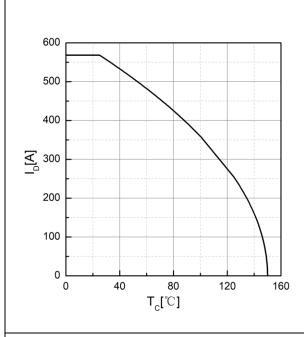












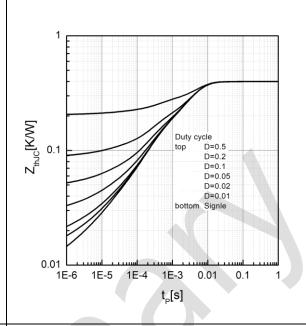


Figure 13. Drain current

Figure 14. Effective Transient Thermal Impedance

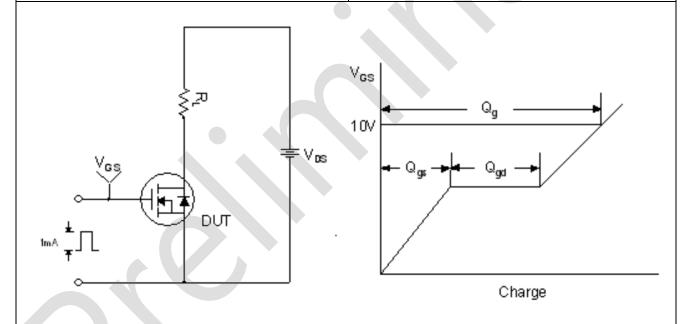


Figure 15. Gate Charge Test Circuit & Waveform



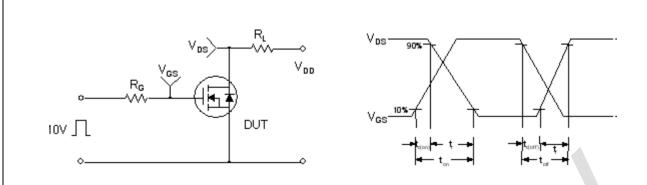


Figure 16. Resistive Switching Test Circuit & Waveforms

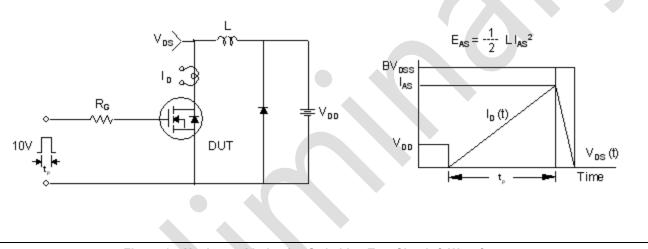
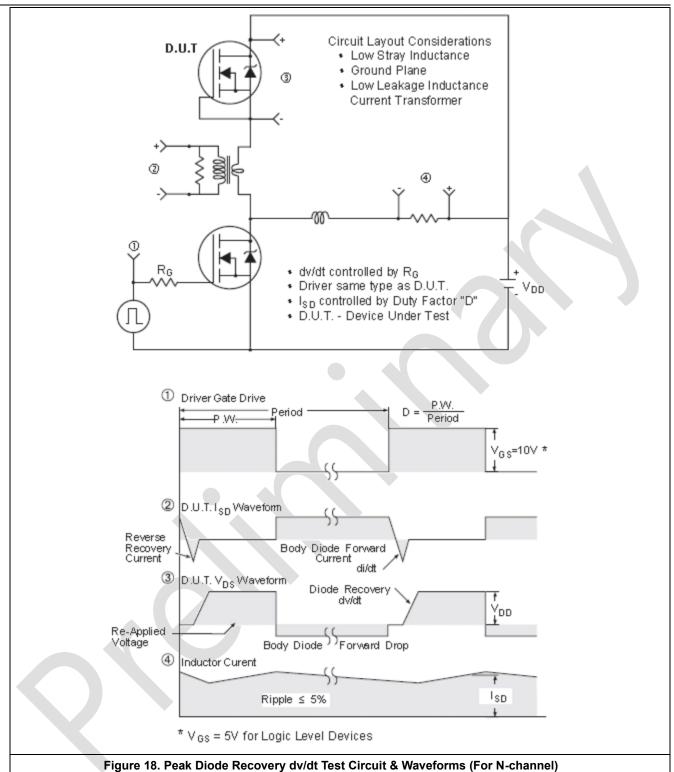


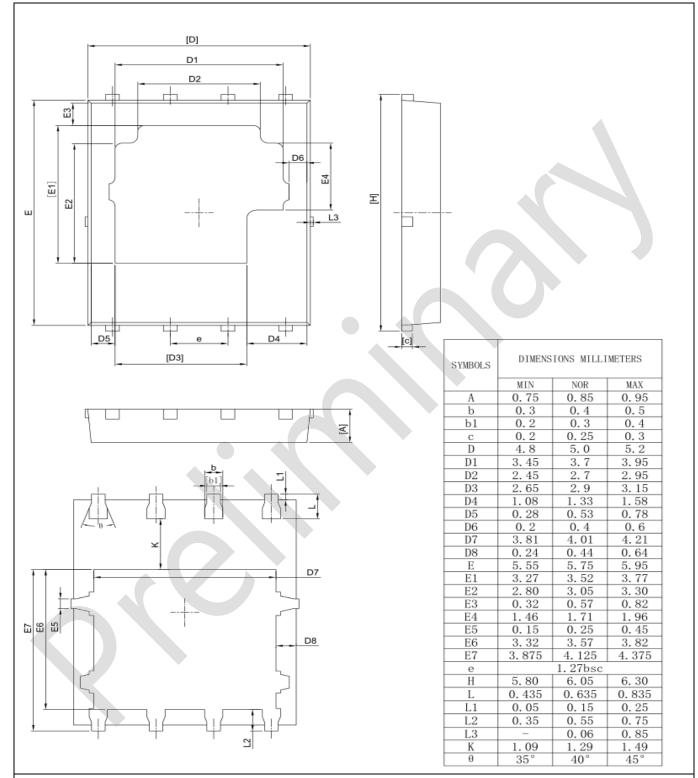
Figure 17. Unclamped Inductive Switching Test Circuit & Waveforms







### Package outline





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